

# **BC184C**

# Silicon NPN Small Signal Transistor (Note 1)

- BV<sub>CEO</sub> = 30V (Min.)
   h<sub>FE</sub> = 130 (Min.) @V<sub>CE</sub> = 5.0V, I<sub>C</sub> = 100mA



1. Collector 2. Base 3. Emitter

### **Absolute Maximum Ratings** T<sub>C</sub>=25°C unless otherwise noted

Symbol	Parameter	Value	Units
V <sub>CBO</sub>	Collector-Base Voltage	45	V
V <sub>CEO</sub>	Collector-Emitter Voltage	30	V
V <sub>EBO</sub>	Emitter-Base Voltage	5	V
I <sub>C</sub>	Collector Current (DC)	500	mA
P <sub>C</sub>	Collector Dissipation (T <sub>a</sub> =25°C) (Note 2, 3)	350	mW
TJ	Junction Temperature	150	°C
T <sub>STG</sub>	Storage Temperature	- 55 ~ 150	°C

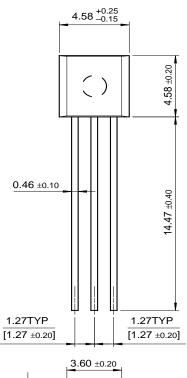
## Electrical Characteristics T<sub>C</sub>=25°C unless otherwise noted

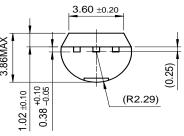
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
BV <sub>CBO</sub>	Collector-Base Voltage	I <sub>C</sub> = 10μA	45	W. W.		V
BV <sub>CEO</sub>	Collector-Emitter Voltage	I <sub>C</sub> = 2mA	30			V
BV <sub>EBO</sub>	Emitter-Base Voltage	I <sub>E</sub> = 10μA	5			V
I <sub>CBO</sub>	Collector Cut-off Current	$V_{CB} = 30V$			15	nA
I <sub>EBO</sub>	Emitter Cut-off Current	V <sub>EB</sub> = 4V			15	nA
h <sub>FE</sub>	DC Current Gain	$V_{CE} = 5V, I_{C} = 10\mu A$ $V_{CE} = 5V, I_{C} = 2mA$ $V_{CE} = 5V, I_{C} = 100mA$	100 250 130		800	
V <sub>CE</sub> (sat)	Collector-Emitter Saturation Voltage	$I_C = 10 \text{mA}, I_B = 0.5 \text{mA}$ $I_C = 100 \text{mA}, I_B = 5 \text{mA}$			0.6 0.25	V
V <sub>BE</sub> (sat)	Base-Emitter Saturation Voltage	I <sub>C</sub> = 100mA, I <sub>B</sub> = 5mA	11/		1.2	V
V <sub>BE</sub> (on)	Base-Emitter On Voltage	$V_{CE} = 5V$ , $I_C = 2mA$	0.55		0.7	V
C <sub>OB</sub>	Output Capacitance	V <sub>CE</sub> = 10V, f = 1MHz		77	5	pF
f <sub>T</sub>	Current gain Bandwidth Product	V <sub>CE</sub> = 5V, I <sub>C</sub> = 10mA 150 f = 100MHz				MHz
h <sub>FE</sub>	Small Signal Current Gain	V <sub>CE</sub> = 5V, I <sub>C</sub> = 2mA 240 f = 1KHz		900		
NF	Noise Figure	$V_{CE} = 5V$ , $I_{C} = 200mA$ $R_{G} = 2K\Omega$ , $f = 30Hz \sim 15KHz$ $V_{CE} = 5V$ , $I_{C} = 200\mu A$ , f = 1KHz			4	dB

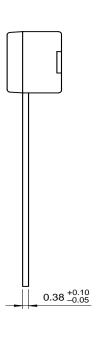
- These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.
   These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
   These ratings are based on a maximum junction temperature of 150degrees C.

# **Package Dimensions**

# TO-92







Dimensions in Millimeters

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